

**Amendments to the Specification**

Please replace the paragraph [0025] beginning at page 5, line 4, with the following amended paragraph:

"Fig. 2 shows the precise cutting device according to the present invention. The precise cutting device 40 includes a microscope 41 and an elevated cutter assembly 44. The microscope 41 ~~40~~ has a movable stage 43, an adjustable lens set 42, a base 49, a support arm 48 and a light source 45. The base 49 positions the precise cutting device 40. The support arm 48 extends upward from the base 49. The stage 43 is disposed on the support arm 48, and supports the test piece 10. The lens set 42 includes eyepieces 421 and objectives 422 to change the amplification of the microscope 41, showing the microstructure of the test piece 10. The light source disposed on the base 49 of the microscope 41 has a lamp facing the opening 431 of the stage 43 to light the test piece 10."